

# KLA Probe Selection Table for RS35/RS50/RS75/RS100

## KT四點探針針頭選擇表

| <b>Probe Type</b> | <b>Part #</b> | <b>Description</b>                          | <b>Application</b>  |
|-------------------|---------------|---|---|
| A                 | 50-0002-01    | 1.6 mil, 100 gm, Tungsten Carbide, 40 mil   | For measuring metals  |
| F                 | 50-0002-10    | 1.6 mil, 100 gm, Tungsten Carbide, 25 mil   |   |
| B                 | 50-0002-02    | 4.0 mil, 100 gm, Tungsten Carbide, 40 mil   | General purpose head for implantation, doped poly, silicides, exitaxy, and diffusion                      |
| G                 | 50-0002-11    | 4.0 mil, 100 gm, Tungsten Carbide, 25 mil   |   |
| C                 | 50-0002-03    | 8.0 mil, 100 gm, Tungsten Carbide, 40 mil   | Specifically designed for high impedance surfaces such as low implant dose, shallow junctions, doped poly |
| H                 | 50-0002-12    | 8.0 mil, 100 gm, Tungsten Carbide, 25 mil   |   |
| D                 | 50-0002-05    | 20.0 mil, 100 gm, Tungsten Carbide, 40 mil  | For very difficult implant and high impedance surfaces beyond 8.0 mil                                     |
| E                 | 50-0002-06    | 1.6 mil, 200 gm, Tungsten Carbide, 62.5 mil | Probe head specific to substrate measurements, i.e. bulk  |